

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2829 Examiner: J. Hollington

**INFORMATION** 

DISCLOSURE STATEMENT

October 18, 2002

In Re NEW PATENT APPLICATION Of:

Applicant: Mikio OHTAKI

KAN 120D1

Appln. No.: 09/904,663

Filed: July 16, 2001

SEMICONDUCTOR DEVICE

TEST METHOD

Commissioner for Patents Washington, D.C. 20231

Sir:

For:

Atty Ref.:

This is an Information Disclosure Statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(c)(2), i.e., after a first Office Action on the merits but before Final Rejection and/or Notice of Allowance, along with the required fee of \$180, under 37 C.F.R. §1.17(p).

A Japanese Office Action dated July 11, 2002 for the corresponding Application cited the document JP 64001252. The publication is cited on the attached Form PTO-1449. Consideration of the document is respectfully requested.

Date

October 18, 2002

10/22/2002 AADDFD1 00000018 09904663

01 FC:1806

180.00 OP

SMR:pjl

Respectfully submitted,

Steven M. Rabin - Reg. No. 29,102

RABIN & BERDO, P.C.

Telephone:

202-371-8976

Telefax:

202-408-0924

CUSTOMER NO. 23995